Analysis of Ti nanolayers irradiated with Xeq+ ions using synchrotron radiation based X-ray reflectometry **[1]**

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Nauka [2]
Zak?ad: Zak?ad Metod Fizycznych [3]

Links
[1] https://onkol.kielce.pl/pl/nauka/analysis-ti-nanolayers-irradiated-xeq-ions-using-synchrotron-radiation-based-x-ray [2] https://onkol.kielce.pl/pl/sekcja/nauka [3] https://onkol.kielce.pl/pl/publikacje-naukowe-kategorie/zaklad-metod-fizycznych